

INCREASE EFFICIENCY AND ACCURACY

Quickly Scan Employee Badges for Reliable Classroom Attendance Records

Easy Scan eliminates the need to manually record attendance from class roster sheets, saving hours of time. Using it, employees swipe their badges as they enter or leave class, and attendance is instantly captured in the HealthStream Learning Center (HLC). When a class is held where the HLC is not accessible, instructors can scan badges with portable scanners or into text files on laptops, which they can then upload and import later. Easy Scan is affordable to implement because it uses your existing badges, computers, and inexpensive scanning devices.

“Managers and directors are requesting Easy Scan for other high attendance activities—for example our Associate Safety Fairs, Employee Benefit Fairs, etc. They like it as well as the associates.”

Diane Fuqua
CHRISTUS
St. Frances Cabrini Hospital

Impact:

Save Time

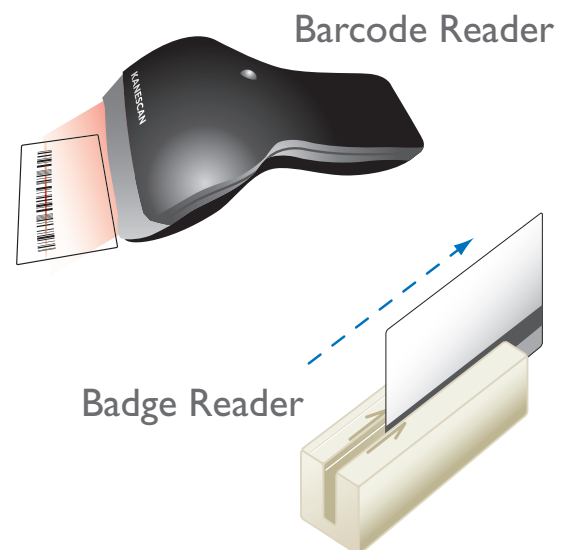
- Process class attendance more quickly so that class starts sooner
- Eliminate the time required to research illegible signatures on Class Rosters

Eliminate Errors

- Display non-sensitive data from the badge to receive instant student acknowledgment
- Transfer and store data in the HLC to reduce human error

Features:

- Completely integrated with the HLC
- Badge IDs can differ from HealthStream IDs
- Process two sign-up lines at the same time by using a “Y” connector on your PC’s USB port
- Card readers available from many different manufacturers
- Ability to manage and update different badge configurations for different facilities
- Reporting functionality included
- Data encrypted for security
- Built using the most current Microsoft technology



Easy Scan captures classroom attendance data quickly, accurately and inexpensively.

About HealthStream

HealthStream (NASDAQ: HSTM) is a leading provider of research and learning solutions for the healthcare industry. HealthStream focuses on turning “Insight into Action” for leading healthcare providers and suppliers through continuous measurement and adaptive learning.